

# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

## Title of Invention

SPECIFIC SITE BACKSIDE UNDERLAYING AND  
MICROMASKING METHOD FOR ELECTRICAL  
CHARACTERIZATION OF SEMICONDUCTOR DEVICES

Application Number :

10/605530

Confirmation Number:

First Named Applicant:

Barbara Averill

Attorney Docket Number:

FIS920030275US1

Art Unit:

2829

Examiner:

Parvash Patel

Search string:

( 5698474 or 5786236 or 5990562 or 6078057 or 6242931 or 6245587 or 6255124  
or 6329212 or 6452209 ).pn

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
<i>10</i>	1	5698474	1997-12-16	Hurley		437	249
	2	5786236	1998-07-28	Thompson et al.		438	60
	3	5990562	1999-11-23	Vallett		257	774
	4	6078057	2000-06-20	Vallett		257	48
	5	6242931	2001-06-05	Hembree et al.	B1	324	754
	6	6245587	2001-06-12	Vallett	B1	438	18
	7	6255124	2001-07-03	Bridsley	B1	438	14
	8	6329212	2001-12-11	Dobrovolski	B1	438	15
<i>10</i>	9	6452209	2002-09-17	Vallett	B2	257	48

## Signature

Examiner Name

Date

*Parvash Patel*

*12/06/04*

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

FIS920030275US1

Application Number

10/605,530

Applicant(s)

BARBARA A. AVERILL ET AL.

Filing Date

10/06/2003

Group Art Unit

NYA

2829

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

1	<del>http://www.hypervisioninc.com/procu2.htm</del> <del>chip UnZip™</del>	12/06 Not considered because not complete 2 pages 09/18/2003 Also page can't be found on web.
2	M. Mahanpour et al.; "Die and Solder Ball Defect Inspection in Flip Chipped Packaged Devices;" found at http://www.fabtech.org/features/tap/articles/06.433.html	Total 9 pages. 09/18/2003

EXAMINER

*T. Smith*

DATE CONSIDERED

12/06/04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.